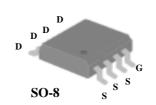
# **Pb Free Plating Product**



P-CHANNEL ENHANCEMENT MODE
POWER MOSFET

- **▼** Simple Drive Requirement
- **▼** Low On-resistance
- **▼** Fast Switching Characteristic

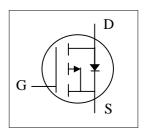


BV <sub>DSS</sub>	-30V		
R <sub>DS(ON)</sub>	14m $\Omega$		
I <sub>D</sub>	-10.7A		

### **Description**

The Advanced Power MOSFETs from APEC provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The SO-8 package is universally preferred for all commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters.



## **Absolute Maximum Ratings**

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	-30	V
$V_{GS}$	Gate-Source Voltage	± 25	V
I <sub>D</sub> @T <sub>A</sub> =25°C	Continuous Drain Current <sup>3</sup>	-10.7	Α
I <sub>D</sub> @T <sub>A</sub> =70°C	Continuous Drain Current <sup>3</sup>	-8.6	Α
I <sub>DM</sub>	Pulsed Drain Current <sup>1</sup>	-50	Α
P <sub>D</sub> @T <sub>A</sub> =25°C	Total Power Dissipation	2.5	W
	Linear Derating Factor	0.02	W/°C
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	$^{\circ}\!\mathbb{C}$
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	$^{\circ}\mathbb{C}$

#### **Thermal Data**

Symbol	Parameter		Value	Unit	
Rthj-a	Thermal Resistance Junction-ambient <sup>3</sup>	Max.	50	°C/W	

### **AP4407GM**



Electrical Characteristics@T<sub>j</sub>=25°C(unless otherwise specified)

	,	-		•		
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =-250uA	-30	-	-	V
$\Delta BV_{DSS}/\Delta T_{j}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I <sub>D</sub> =-1mA	-	-0.015	-	V/°C
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-10V, I <sub>D</sub> =-10A	-	-	14	$m\Omega$
		$V_{GS}$ =-4.5V, $I_D$ =-5A	-	-	20	$\mathbf{m}\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{D}=-250uA$	-1	-	-3	V
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =-10V, I <sub>D</sub> =-10A	-	13	-	S
I <sub>DSS</sub>	Drain-Source Leakage Current (T <sub>j</sub> =25°C)	$V_{DS}$ =-30V, $V_{GS}$ =0V	-	-	-1	uA
	Drain-Source Leakage Current (T <sub>j</sub> =70°C)	$V_{DS}$ =-24V, $V_{GS}$ =0V	-	-	-25	uA
I <sub>GSS</sub>	Gate-Source Leakage	$V_{GS} = \pm 25V$	-	-	±100	nA
$Q_g$	Total Gate Charge <sup>2</sup>	I <sub>D</sub> =-10.7A	-	29	46	nC
$Q_{gs}$	Gate-Source Charge	V <sub>DS</sub> =-24V	-	6	-	nC
$Q_{gd}$	Gate-Drain ("Miller") Charge	V <sub>GS</sub> =-4.5V	-	14	-	nC
t <sub>d(on)</sub>	Turn-on Delay Time <sup>2</sup>	V <sub>DS</sub> =-15V	-	15	-	ns
t <sub>r</sub>	Rise Time	I <sub>D</sub> =-1A	-	12	-	ns
$t_{d(off)}$	Turn-off Delay Time	$R_G=3.3\Omega, V_{GS}=-10V$	-	100	-	ns
t <sub>f</sub>	Fall Time	$R_D=15\Omega$	-	70	-	ns
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V	-	2600	4100	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =-25V	-	500	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	f=1.0MHz	-	370	-	pF

### **Source-Drain Diode**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
$V_{SD}$	Forward On Voltage <sup>2</sup>	I <sub>S</sub> =-10.7A, V <sub>GS</sub> =0V	1	ı	-1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>S</sub> =-10.7A, V <sub>GS</sub> =0V,	1	31	-	ns
$Q_{rr}$	Reverse Recovery Charge	dl/dt=100A/µs	-	25	-	nC

#### Notes:

- 1. Pulse width limited by Max. junction temperature.
- 2.Pulse width <300us, duty cycle <2%.
- 3.Surface mounted on 1 in  $^2$  copper pad of FR4 board ; 125  $^{\circ}$ C/W when mounted on min. copper pad.



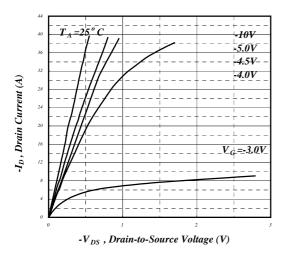


Fig 1. Typical Output Characteristics

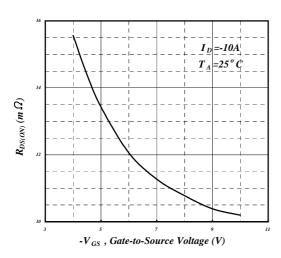


Fig 3. On-Resistance v.s. Gate Voltage

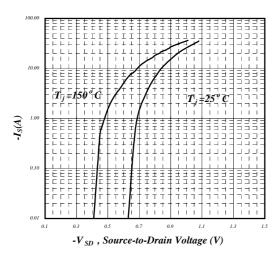


Fig 5. Forward Characteristic of Reverse Diode

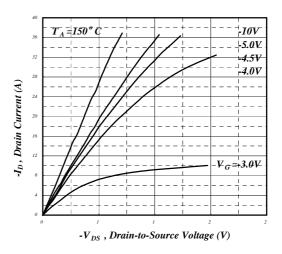


Fig 2. Typical Output Characteristics

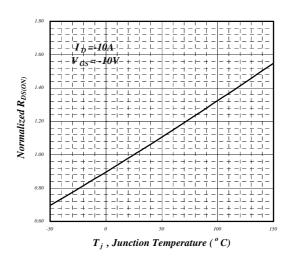


Fig 4. Normalized On-Resistance v.s. Junction Temperature

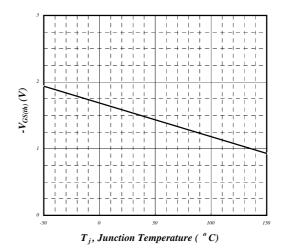


Fig 6. Gate Threshold Voltage v.s. Junction Temperature



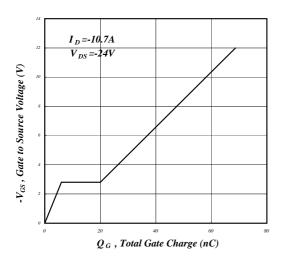


Fig 7. Gate Charge Characteristics

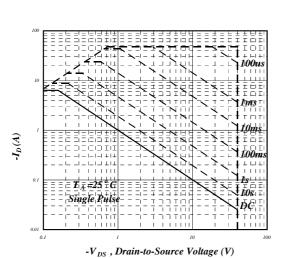


Fig 9. Maximum Safe Operating Area

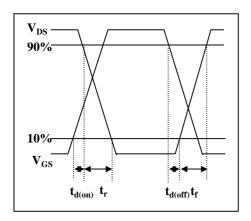


Fig 11. Switching Time Waveform

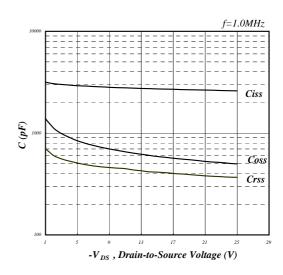


Fig 8. Typical Capacitance Characteristics

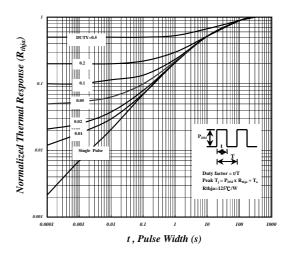


Fig 10. Effective Transient Thermal Impedance

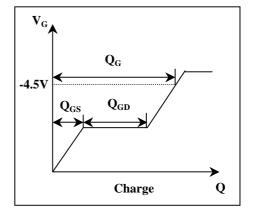


Fig 12. Gate Charge Waveform